

Search Notes

Application/Control No.

10/626,693

Examiner

Madeleine AV Nguyen

Applicant(s)/Patent under
Reexamination

MEYER, JOHN F.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
358	1.9	10/11/2006	AV
	1.15		
	400		
	442		
	444		
	468		
379	100.01		
358	500		
	1.15		
358	1.16		
	1.13		
358	1.1		
348	207.1		
348	207.2	10/11/2006	AV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	10/11/2006	AV
East	10/12/2006	AV